Low-level Elemental Analysis of Filters

Julia SedImair, Bruker AXS LLC, 5465 E Cheryl Pkwy, Madison, WI-53711, USA

Objective

XRF analysis of liquids is common but the risk of a sample spill is never totally avoided. Using filters instead has several advantages:

- The samples can be measured in vacuum
 - No He necessary
 - Better detection for light elements
- No sample breakages
- Filters produce less waste
- Less sample is needed

Usually an ED-XRF system is used for filter analysis, because high power WD-XRF instruments might damage the filter.

However, it can be tricky to measure certain elements due to the configuration of most ED-XRF spectrometers. Low levels of heavier elements can be hard to achieve, if the excitation energy is not sufficient or sum peaks and escape peaks interfere with the signal. The characteristic lines of lighter elements of interest (S, P, Cl) often interfere with the L-lines of most X-ray tubes, so measuring lower concentrations is challenging. These challenges are overcome when using a low power WD-XRF

system. Here we demonstrate the analysis of low levels of Br and Cl using a 400W WD-XRF spectrometer, Bruker's S6 Jaguar.

Sample Preparation and Standards

Known amounts of solutions with defined concentrations of CI and Br were filtered through a to make standards.

For unknown samples, the same amount as for the standards were filtered

The filter was dried and cut to the right size (hole punch, 38 mm)







	Std-1	Std-2	Std-3	Std-4	Std-5	Std-6
CI [PPM]	100	200	300	400	500	700
Br [PPM]	5	10	15	20	25	35

Method

The method was simple using default crystals as commonly used in the industry – PET for CI, Li200 for Br – and measuring peak / background for 120 s / 30 s for CI and 180 s / 60 s for Br.



The calibration curves show great correlation and a small standard deviation.



Calibration Co	efficients	Calibration Coefficients			
Standard deviation	22.6 PPM	Standard deviation	0.3 PPM		
Squared correlation coefficient	0.99189	Squared correlation coefficient	0.99959		



Results

To check the results 2 samples were tested and a repetition test was run. The control samples show great accuracy of the calibration. The repeatability is outstanding and shows that samples can be remeasured without having to worry about radiation damage to the sample.

				CI (F	PPM)	Br (P	PM)	
	C 4	Gi	ven		630		38	
	C1 5		66	633.5		38.2		
	C 0	Gi	ven		400		20	
	C2	S	66		388.1		20.1	
Pop #			Br (D			Cncl	Br /l	Cncl
кер#						ch2)		Ch2)
1		631		38	2	1.107		1.115
2		632		38	2	1.147		1.118
3		632		38	2	1.160		1.114
4		633		38	2	1.195		1.124
5		633		38	2	1.172		1.122
6		634		38	2	1.204		1.125
7		635		38	2	1.257		1.125
8		634		39	2	1.203		1.127
9		633		39	2	1.195		1.126
10		635		39	2	1.251		1.128
11		635		38	2	1.231		1.123
12		635		39	2	1.259		1.128
AVG		634		38	2	1.198		1.123
SD		1.4		0.5		0.0		0.0
RSD	0.	22%	1	.28%	C	.22%		0.42%

Conclusions

- The S6 Jaguar is the perfect instrument when high resolution WD-XRF measurements of radiation-sensitive samples is needed
- This measurements are straightforward and low levels of challenging elements like CI, P and S or elements heavier than Rh can analyzed with a few clicks.
- The principle of this application can easily be transferred to water treatment processes, measuring biofluids and pharmaceutical solutions and petrochemical products.
- The detection limit and the statistical error are below 1 ppm.

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